

ATTACH #15

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 107351-00001	SERIAL NO. 09/589,225
		APPLICANT NAKAHIGASHI et al.	
		FILING DATE June 8, 2000	GROUP 1775

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						


FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO PART.		
	AC	64-00484	04/06/1989	Japan					X
	AH	63-217303	09/09/1988	Japan					X
	AI	64-090484	04/06/1989	Japan					X
	AJ	63-217303	09/09/1988	Japan					x
	AK	09-160457	06/20/1997	Japan					X
	AL								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AM	
	AN	
	AO	

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TC 1700

EXAMINER 	DATE CONSIDERED 10/19/02
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FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 107351-00001	SERIAL NO. Unknown Division of 08/884,554
LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		APPLICANT NAKAHIGASHI, et al.	
		FILING DATE June 13, 2000	GROUP

10835 U.S. PTO
09/58925
06/08/00

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA	4,996,079	02/26/91	Itoh	—	—	
	AB	5,368,937	11/29/94	Itoh	—	—	
	AC						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION		
							YES	NO	PART
	AD	1-2948673	11/28/89	Japan	—	—	X		
	AE	2-166283	06/26/90	Japan	—	—	X		
	AF	3-240959	10/28/91	Japan	—	—	X		
	AG	6-291048	10/18/94	Japan	—	—	X		
	AH	330 524	08/30/89	Europe	—	—			
	AI	1035855A	09/27/89	China	—	—		X	
	AJ	2-80571	03/20/90	Japan	—	—	X		
	AK	3-189613	08/19/91	Japan	—	—	X		
	AL	5-13394	01/22/93	Japan	—	—	X		
	AM	5-41368	02/19/93	Japan	—	—	X		
	AN	7-187862	07/25/95	Japan	—	—	X		

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AO	
	AP	
	AQ	

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
JF	BA	5,039,548	8/91	Hirose et al.	427	536
	BB	5,521,351	5/96	Mahoney	219	121.59
A	BC	5,562,952	10/96	Nakahigashi et al.	427	534
						11/94

FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS									
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION		
							YES	NO	PART
JF	BD	8-74032	03/19/96	Japan	7	7	X		
	BE	7-278822	10/24/95	Japan			X		
	BF	9-12750	01/14/97	Japan			X		
	BG	9-78226	03/25/97	Japan			X		
	BH	9-95784	04/08/97	Japan			X		
	BI	9-124807	05/13/97	Japan			X		
	BJ	9-125253	05/13/97	Japan			X		
	BK	9-173192	07/08/97	Japan			X		
	BL	WO97/10688	03/20/97	PCT			X		
	A	BM	5-117087	05/93			Japan	7	7
BN		5-237709	09/93	Japan					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	BO	
	BP	
	BQ	

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EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	CA						
	CB						
	CC						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO PART		
<i>J</i>	CD	0 653 501 A1	5/17/95	Europe	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>			
<i>CE</i>	CE	0 330 524 A	08/30/89	Europe					
<i>CF</i>	CF	03-130363 A	06/04/91	Japan (with English abstract from JPO)	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>			
<i>CG</i>	CG	04-041672	02/12/92	Japan (with English abstract from JPO)	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>			
	CH								
	CI								
	CJ								
	CK								
	CL								
	CM								
	CN								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>WP</i>	CO	Athwal et al., Diamond and Related Materials, vol. 2, pp. 1483-1489, November 1, 1993
<i>CP</i>	CP	Derwent Abstract No. AN 1991-204818, 1991; Derwent Abstract No. AN 1992-100016, 1992

EXAMINER	<i>hume</i>	DATE CONSIDERED	<i>10/15/0</i>
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